Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/705,347	LABELLE ET AL.
Examiner	Art Unit
Kin-Chan Chen	1765

	SEARCHED						
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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EAST key words search, USPAT, US-PGPUB, EPO, JPO, Derwent, IBM-TDB, inventor search.	8/1/2005	ксс		
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